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9. M. Pátek, H. Kobayashi, M. Takahashi, N. Fujiwara, J. Rusnák and E. Pinčík: Q-DLTS of cyanide treated very thin SiO<sub>2</sub>/a-Si:H/c-Si structures
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11. J. Rusnák, A. Morales, M. Jergel and E. Pinčík: On electrical properties of very thin silicon nitrided oxide films prepared in N<sub>2</sub>O atmosphere at high temperature
12. M. Seberíni, J. Degmová: CEMS Measurement of Thin Iron-Containing Surface Layers and Some Problems Encountered in Real Measurement
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